

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BAJAJ ET AL.
		10/074,141 Examiner Edna Wong <i>EDNA WONG</i>	Art Unit 1753
		Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2002/0127847	09-2002	Alling et al.	438/630
	C	US-			
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	A	US-3,915,717	10-1975	Feldstein et al.	106/1.23
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*	B	US-4,282,271	08-1981	Feldstein, Nathan	427/98
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